D3449, MARCH 1990-REVISED OCTOBER 1990

- Inputs are TTL-Voltage Compatible
- **High-Speed Bus Transceivers With Parity** Generator/Checker
- Parity-Error-Flag Open-Drain Output
- Register for Storage of the Parity-Error Flag
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

description

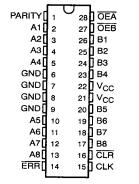
The 'ACT11833 is an 8-bit to 9-bit parity transceiver designed for two-way communication between data buses. When data is transmitted from the A bus to the B bus, a parity bit is generated. When data is transmitted from the B bus to the A bus with its corresponding parity bit, the ERR output will indicate whether or not an error in the B data has occurred. The output enable inputs $\overline{\text{OEA}}$ and $\overline{\text{OEB}}$ can be used to disable the device so that the buses are effectively isolated.

A 9-bit parity generator/checker generates a parity-odd output (PARITY) and monitors the parity of the I/O ports with an open-drain parity

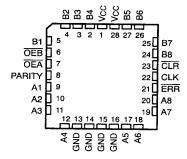
error flag (ERR). ERR is clocked into the register on the rising edge of the CLK input. The error flag register is cleared with a low pulse on the $\overline{\text{CLR}}$ input. When both $\overline{\text{OEA}}$ and $\overline{\text{OEB}}$ are low, data is transferred from the A bus to the B bus and inverted parity is generated. Inverted parity is a forced error condition that gives the designer more system diagnostic capability.

The 54ACT11833 is characterized for operation over the full military temperature range of $-55^{\circ}C$ to $125^{\circ}C$. The 74ACT11833 is characterized for operation from - 40°C to 85°C.

54ACT11833 . . . JT PACKAGE 74ACT11833 . . . DW OR NT PACKAGE (TOP VIEW)



54ACT11833 . . . FK PACKAGE (TOP VIEW)



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Function Table

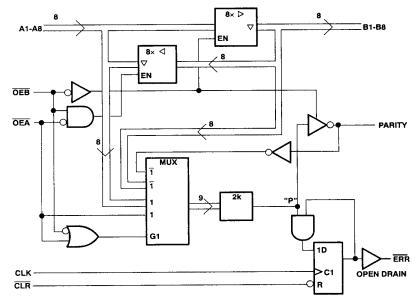
		INPUTS					OUTF	UT AND I/O		
OEB	ŌĒĀ	CLR	CLK	Ai Σ of H's	Bi [†] Σ of H's	А	В	PARITY	ERR	FUNCTION
L	Н	х	×	Odd Even	NA	NA	Α	L H	NA	A data to B bus and Generate Parity
Н	L	н	f	NA	Odd Even	В	NA	NA	H	B Data to A Bus and Check Parity
×	×	L	×	Х	Х	Х	NA	NA	н	Clear Error Flag Register
н	н	H H H	No† No† †	X X Odd Even	×	z	z	z	SHHL	Isolation [‡]
L	L	Х	х	Odd Even	NA	NA	Α	H	NA	A Data to B Bus and Generate Inverted Parity

NA = Not applicable, NC = No change, X = Don't care

† Summation of high-level inputs includes PARITY along with Bi inputs.

‡ In this mode, the ERR output, when clocked, shows inverted parity of the A bus.

logic diagram (positive logic)





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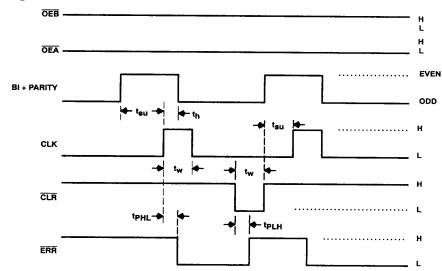
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Error-Flag Function Table

INP	INPUTS INTERNAL TO DEVICE		OUTPUT PRE-STATE	ОИТРИТ	FUNCTION		
CLR	CLK	POINT "P"	ERR n-1	ERR			
Н	†	н	Н	Н			
н	t	×	L	L	Sample		
Н	t	L	×	L			
٦	Х	X	×	н	Clear		

ERR n-1 represents the state of the ERR output before any changes at CLR, CLK, or point "P".

error-flag waveforms



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54ACT11833, 74ACT11833 8-BIT TO 9-BIT PARITY BUS TRANSCEIVERS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	– 0.5 V to 7 V
Input voltage range, V _I (see Note 1)	0.5 V to V _{CC} + 0.5 V
Output voltage range, VO (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V _{CC} or GND pins	±225 mA
Storage temperature range	65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions

		54	54ACT11833			74ACT11833		
		MIN	MIN NOM MAX		MIN	MIN NOM MAX		UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	٧
VIH	High-level input voltage	2			2			٧
VIL	Low-level input voltage			0.8			8.0	٧
VI	Input voltage	0		Vcc	0		Vcc	٧
Vo	Output voltage	0		Vcc	0		Vcc	V
ЮН	High-level output current			- 24			- 24	mA
lOL	Low-level output current			24			24	mA
Δt/Δν	Input transition rise or fall rate	0		10	0		10	ns/V
TA	Operating free-air temperature	- 55		125	- 40		85	°C



electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V	T,	T _A = 25°C			11833	74ACT11833			
PAHAMETER		TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
		I 50A	4.5 V	4.4			4.4		4.4			
		IOH ≃ 50 μA	5.5 V	5.4			5.4		5.4		İ	
V	All outputs except		4.5 V	3.94			3.7		3.8			
VOH	ERR	1 _{OH} = -24 mA	5.5 V	4.94			4.7		4.8		٧	
		I _{OH} = - 50 mA [†]	5.5 V				3.85					
	1	I _{OH} = - 75 mA [†]	5.5 V						3.85			
			4.5 V			0.1		0.1		0.1		
		10L = 50 µA	5.5 V			0.1		0.1		0.1		
\/-·			4.5 V			0.36		0.5		0.44		
VOL		I _{OL} = 24 mA	5.5 V			0.36		0.5		0.44	V	
		IOL = 50 mA [†]	5.5 V					1.65				
		I _{OL} = 75 mA [†]	5.5 V							1.65		
l ₁	OEA, OEB, CLK, and CLR	VI = VCC or GND	5.5 V			± 0.1		± 1		± 1	μΑ	
loz	A or B ports, PARITY‡	VO = VCC or GND	5.5 V			± 0.5		± 10		± 5	μА	
ICC		VI = VCC or GND, IO = 0	5.5 V			8		160		80	μА	
ΔICC§		One input at 3.4 V, Other inputs at GND or VCC	5.5 V			0.9		1		1	mA	
Ci	OEA, OEB, CLK, and CLR	V _I = V _{CC} or GND	5∨		4.5							
Cio	A or B ports, PARITY	VO = VCC or GND	5 V		12						рF	

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Note 2)

			T _A = 25°C	54ACT118	33 74ACT1183	13
			MIN MA	X MIN M	AX MIN M	UNIT
		CLK high	5	5	5	
tw	Pulse duration	CLK low	5	5	5	ns
		CLR low	5	5	5	
^t su	Cohardina bataa Clist	Bi and PARITY	14	14	14	
	Setup time before CLK†	CLR inactive	2	2	2	ns
t _h _	Hold time after CLK †, Bi and PARITY		0	0	0	ns

NOTE 2: Load circuit and voltage waveforms are shown in Section 1.

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25 ^{\circ}\text{C}$

	PARAMETER	TEST CO	TYP	UNIT			
		Outputs enabled	A to B	0		87	
C _{pd}	Power dissipation capacitance per transceiver		B to A	C _L = 50 pF,	f = 1 MHz	60	pF
	one dissipation capacitatice per transceiver	Outputs disabled	A to B	C. 50.55	4 4 5 41 1-	28	
			B to A	C _L = 50 pF,	f = 1 MHz	8	pF



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 $[\]mbox{‡ For I/O$ ports, the parameter IOZ$ includes the input leakage current.}$

^{\$} This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V to VCC.